

DRAM Simulator

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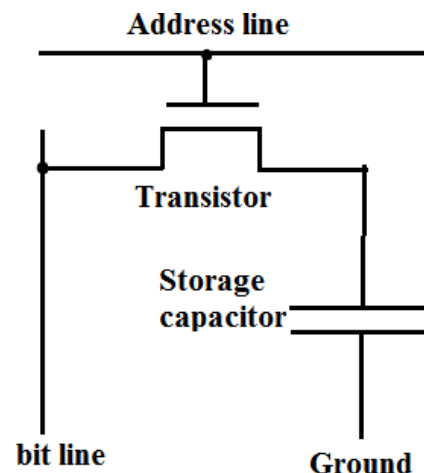
Date: 2024/11/6

Outline

Advanced VLSI
System Design
(Graduate Level)
Fall 2024

- Introduction
- DRAM controller
- Simplified DRAM Simulator
 - Timing Specification
 - Waveform

- ▶ Dynamic random-access memory (dynamic RAM or DRAM) is a type of random-access semiconductor memory.
- ▶ Consisting only a capacitor and a transistor for each bit of data.
- ▶ The electric charge on the capacitors slowly leaks off.
 - ▶ refresh!

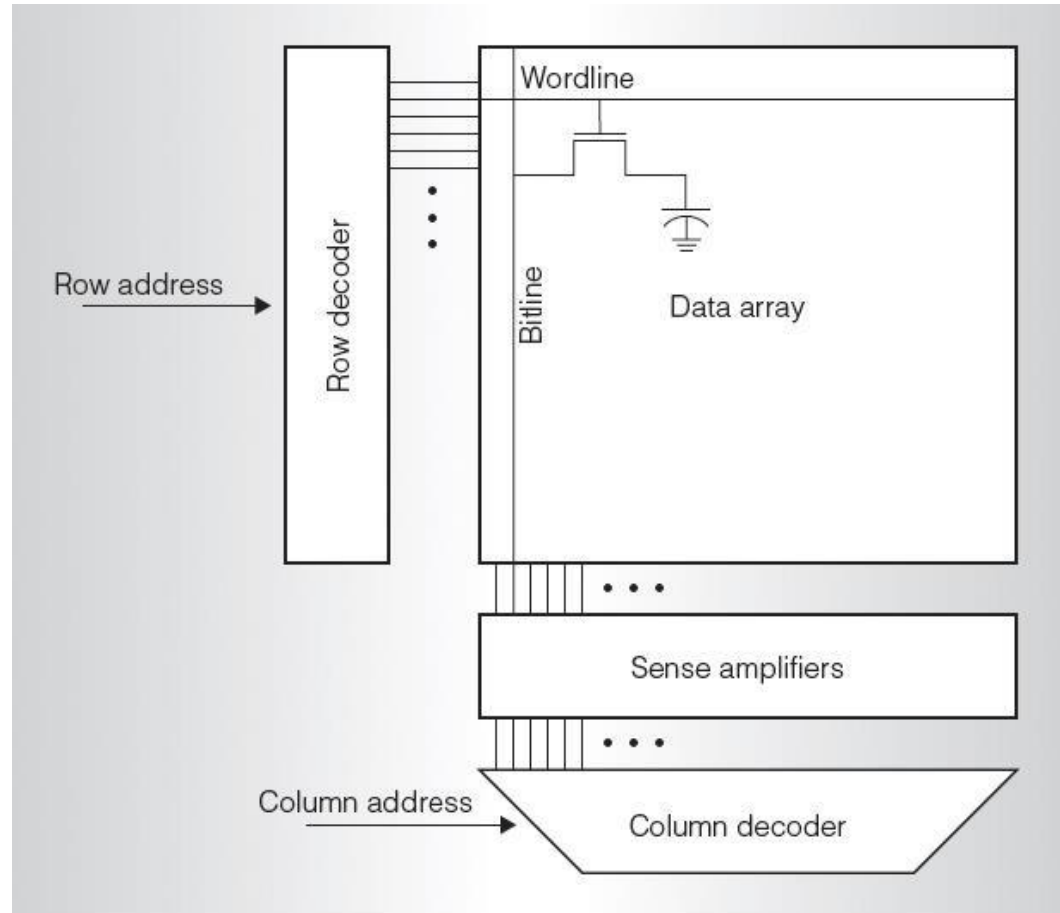


Introduction

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Three Basic Operations

- Row Access
- Column Access
- Pre-charge

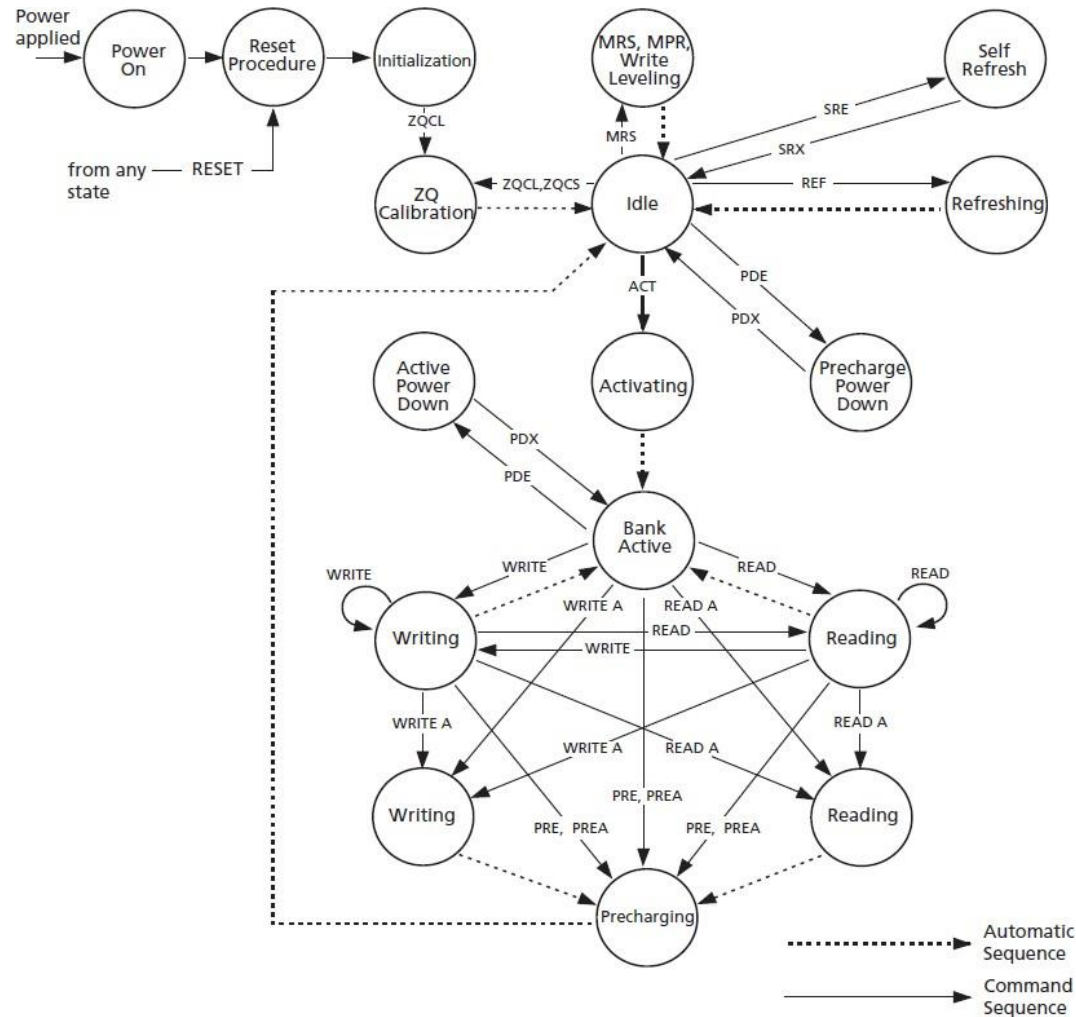


- Ensure correct operation of DRAM
 - Address Mapping, refresh and timing
- Translate request to DRAM command sequences
- Buffer and schedule requests to improve performance
 - Reordering, row-buffer, bank, rank, bus management
- Manage power consumption and thermals in DRAM
 - Turn off/on DRAM chips, manage power modes

DRAM controller

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State diagram



Simplified DRAM Simulator

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Act : Activate row

- RASn = low
- CASn = high
- WEn = 4'hf

READ: Read operation and access column address

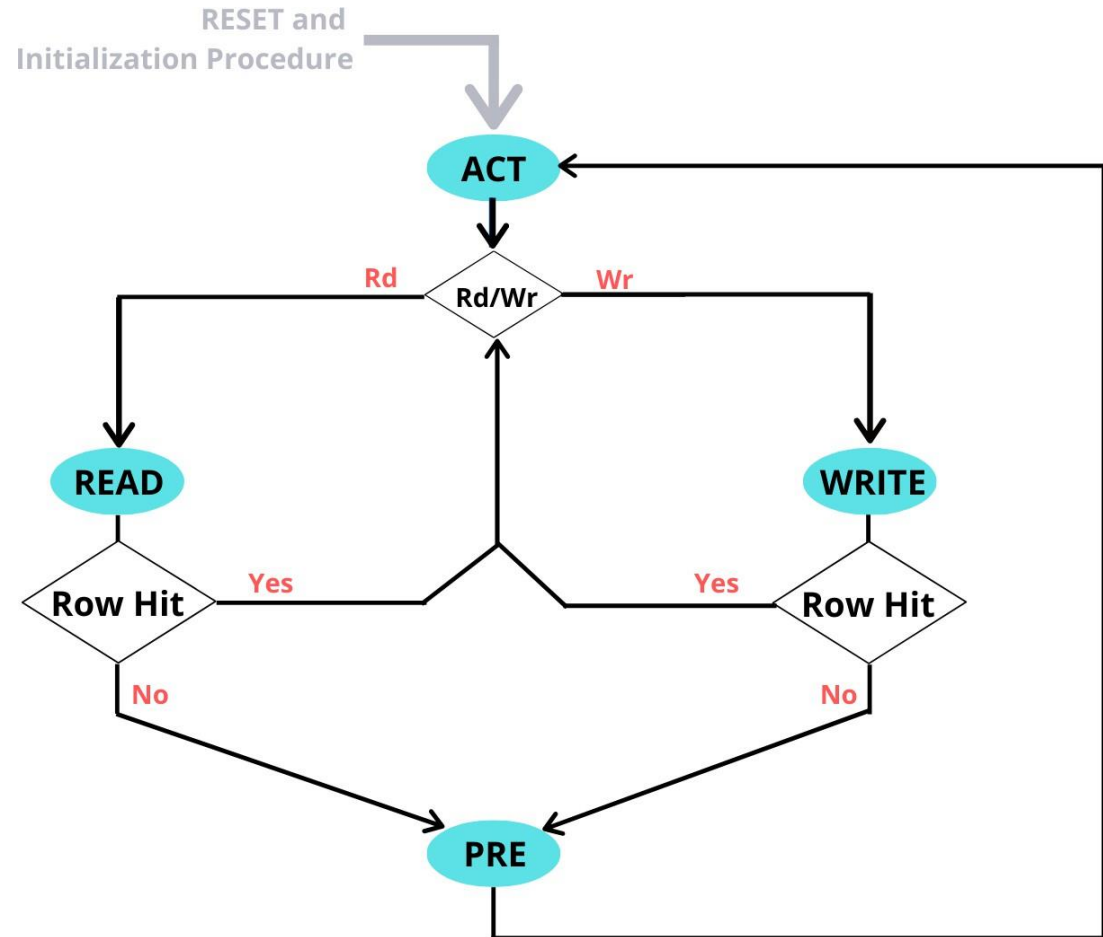
- RASn = high
- CASn = low
- WEn = 4'hf

WRITE: Write operation and access column address

- RASn = high
- CASn = low
- WEn = 4'h0 (for a word)

PRE : Pre-charge

- RASn = low
- CASn = high
- WEn = 4'h0
- The address should be the same as the one that activated last time.



Simplified DRAM Simulator

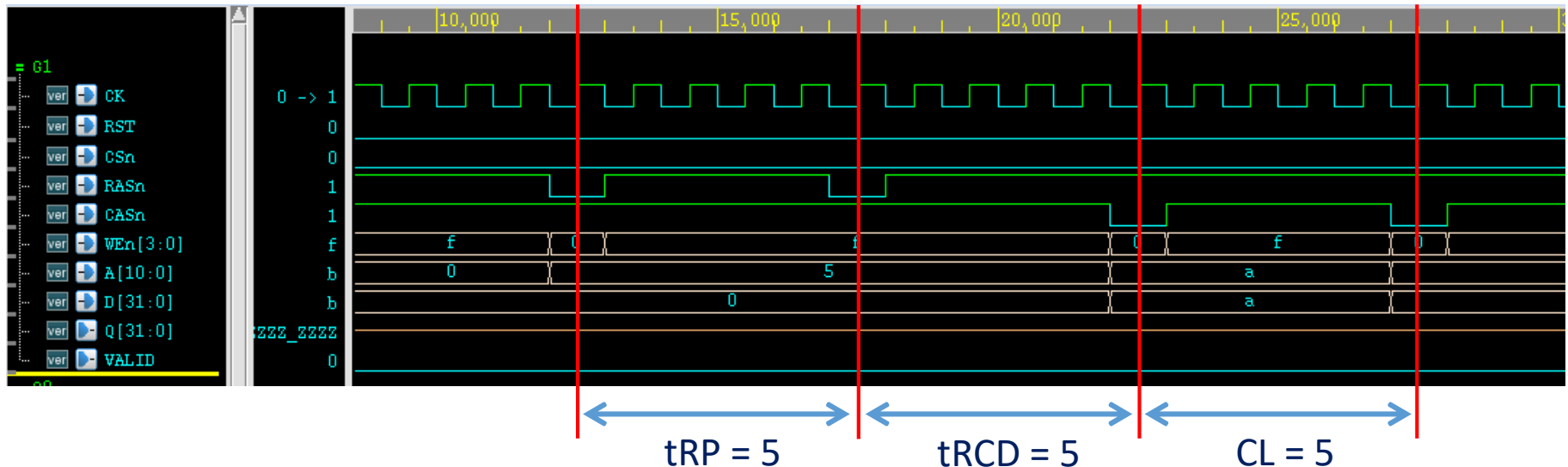
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DRAM	System signals			
	CK	input	1	System clock
	RST	input	1	System reset (active high)
	Memory ports			
	CSn	input	1	DRAM Chip Select (active low)
	WEn	input	4	DRAM Write Enable (active low)
	RASn	input	1	DRAM Row Access Strobe (active low)
	CASn	input	1	DRAM Column Access Strobe (active low)
	A	input	11	DRAM Address input
	D	input	32	DRAM data input
	Q	output	32	DRAM data output
	VALID	output	1	DRAM data output valid
	Memory space			
	Memory_byte0	reg	8	Size: [0:2097151]
	Memory_byte1	reg	8	Size: [0:2097151]
	Memory_byte2	reg	8	Size: [0:2097151]
	Memory_byte3	reg	8	Size: [0:2097151]

★ Row address is 11-bit and column address is 10-bit

Timing Specification

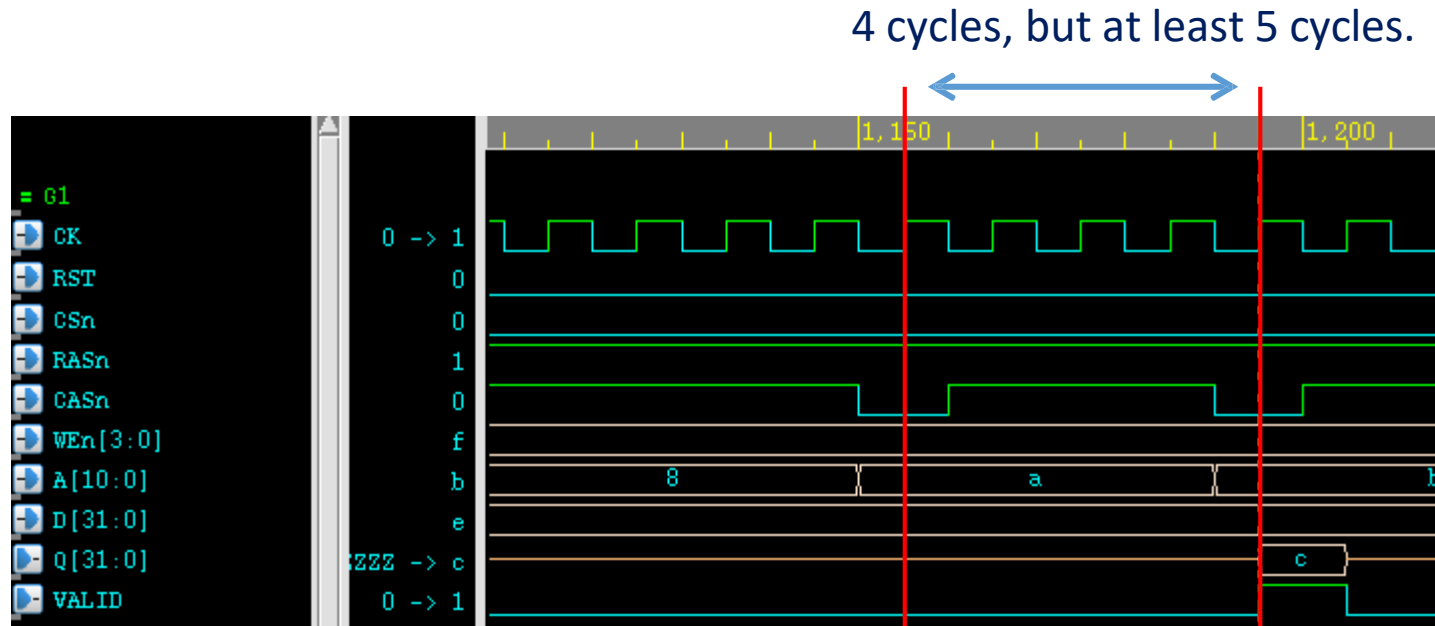
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- tRP** -Precharge Time
Delay time until the next RAS is asserted
- tRCD** -Row Address to Column Address Delay
Active to Read/Write command time
- CL** -CAS Latency
Delay time between the READ command and the moment data is available

Timing Specification

- If the transition violates the timing specification, it will show error or terminates the execution .



```
ncsim: *E,ASRTST (./DRAM.sv,149): (time 1195 NS) Assertion test.M1.CL_check has failed
*** CL Violation ! CASn should have more than 5 cycles interval ***
```

Waveform

➤ RAS → Set Row

➤ A should be ready

➤ CAS → Set Column

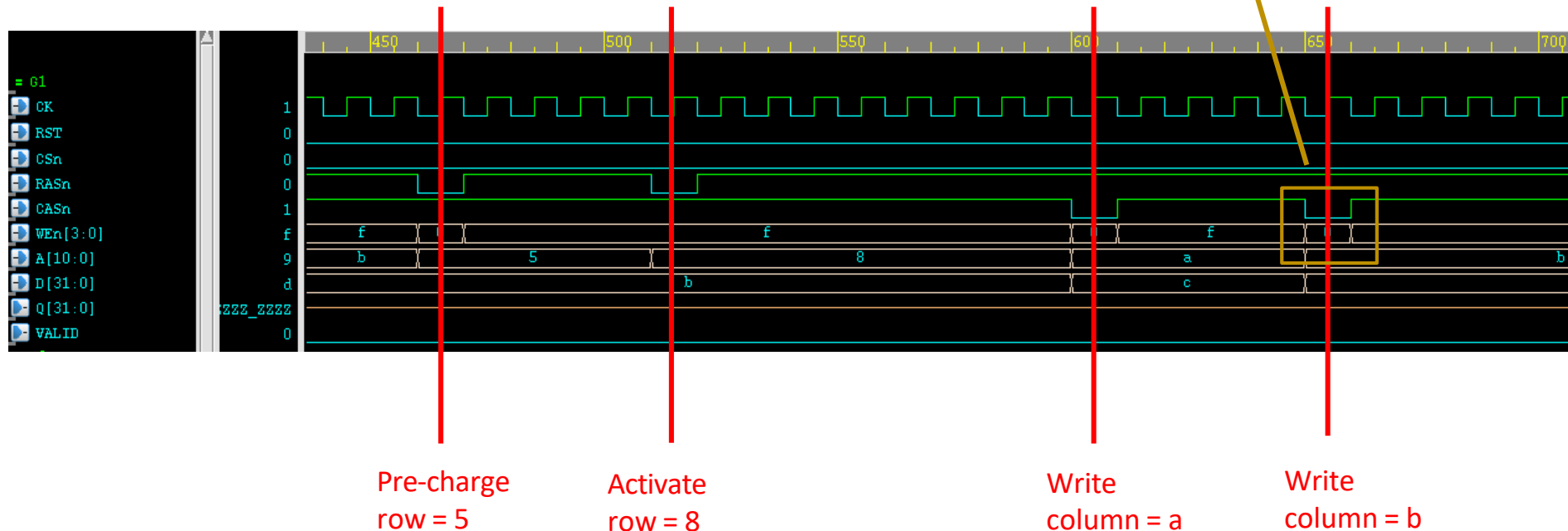
➤ READ : A and WEn should be ready

➤ WRITE : A, WEn and D should be ready

Read/Write command Registration

READ if WEn = 4'hf

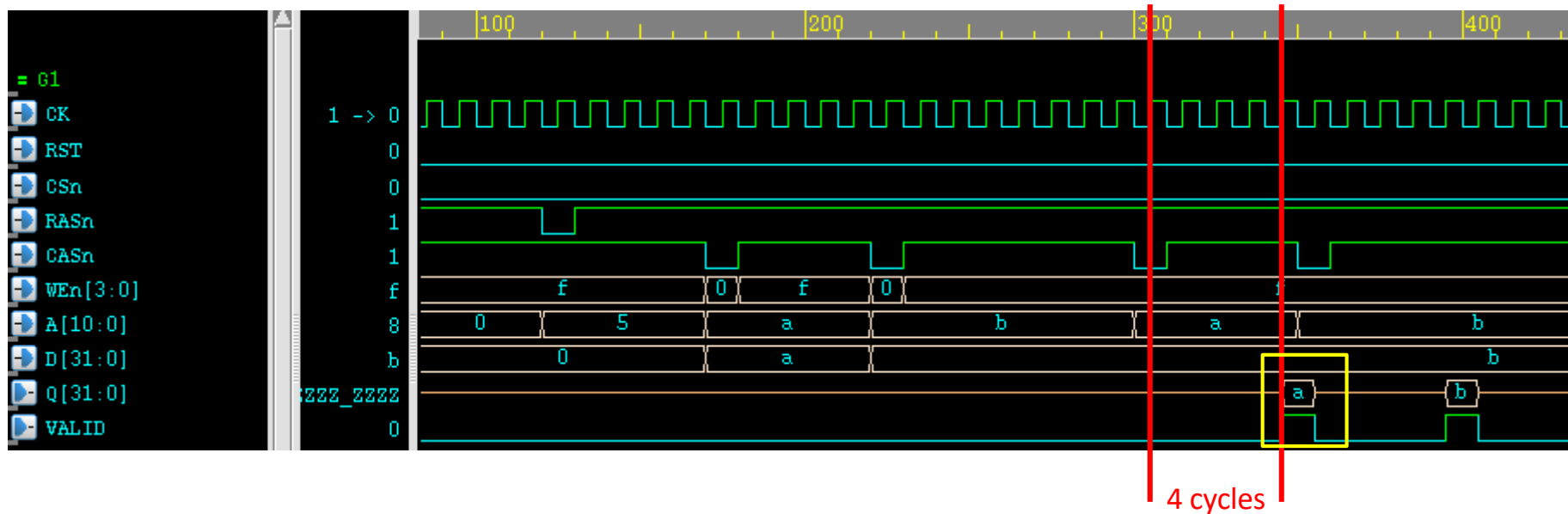
WRITE if WEn != 4'hf



Waveform

Read operation

➤ Data will output with a valid signal



Thanks for listening